

TSA50N25M

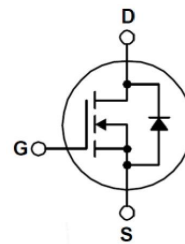
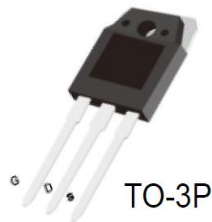
250V N-Channel MOSFET

General Description

This Power MOSFET is produced using Truesemi's advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

Features

- 50A, 250V, Max. $R_{DS(on)} = 0.078\Omega$ @ $V_{GS} = 10V$
 - ♦ Fast switching speed
 - ♦ Low gate charge
 - ♦ RoHS compliant device
- Applications
- ♦ Synchronous Rectification
 - ♦ Power Management in Inverter System



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter		Value	Units
V_{DSS}	Drain-Source Voltage		250	V
V_{GS}	Gate-Source Voltage		± 30	V
I_D	Drain Current	$T_C = 25^\circ\text{C}$	50	A
		$T_C = 100^\circ\text{C}$	31.6	A
I_{DM}	Pulsed Drain Current		200	A
E_{AS}	Single Pulsed Avalanche Energy	(Note 1)	1250	mJ
I_{AS}	Single avalanche current		20	A
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)		245	W
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$

* Limited only maximum junction temperature

Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.51	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	50.0	$^\circ\text{C/W}$

Electrical Characteristics T_c=25 °C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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On Characteristics

V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 uA	2	--	4	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 25A	--	0.065	0.078	Ω
R _g	Internal gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz	--	0.8	--	Ω

Off Characteristics

BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 uA	250	--	--	V
I _{DSS}	Drain-source cut-off current	V _{DS} = 250 V, V _{GS} = 0 V	--	--	1	uA
I _{GSS}	Gate leakage current	V _{DS} =0V, V _{GS} =±30V	--	--	±100	nA

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz (Note 3,4)	--	5521	--	pF
C _{oss}	Output Capacitance		--	395	--	pF
C _{rss}	Reverse Transfer Capacitance		--	42	--	pF

Switching Characteristics

t _{d(on)}	Turn-On Time	V _{DD} = 125V, I _D = 50A, R _G = 25 Ω, V _{GS} =10V (Note 3,4)	--	55	--	ns
t _r	Turn-On Rise Time		--	50	--	ns
t _{d(off)}	Turn-Off Delay Time		--	212	--	ns
t _f	Turn-Off Fall Time		--	31	--	ns
Q _g	Total Gate Charge	V _{DS} = 200 V, I _D =50A, V _{GS} = 10 V (Note 3,4)	--	76	--	nC
Q _{gs}	Gate-Source Charge		--	20	--	nC
Q _{gd}	Gate-Drain Charge		--	25	--	nC

Source-Drain Diode Maximum Ratings and Characteristics

I _S	Continuous Source-Drain Diode Forward Current		--	--	50	A
I _{SM}	Pulsed Source-Drain Diode Forward Current		--	--	200	
V _{SD}	Source-Drain Diode Forward Voltage	I _{SD} =50A, V _{GS} = 0 V	--	--	1.2	V
t _{rr}	Reverse Recovery Time	I _{SD} = 50A, V _{GS} = 0 V di _F /dt = 100 A/μs (Note 3,4)	--	271	--	ns
Q _{rr}	Reverse Recovery Charge		--	2.4	--	uC

NOTES:

- 1.L=5mH, IAS=20 VDD=50V, Starting T_J=25℃
- 2.Pulse test: Pulse width≤300us, Duty cycle≤2%
3. Essentially independent of operating temperature typical characteristics
- 4.Guaranteed by design, not subject to production testing.

Typical Electrical Characteristics Curves

Fig. 1 $I_D - V_{DS}$

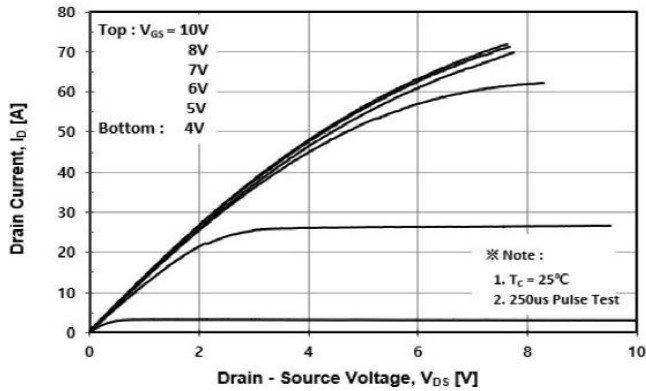


Fig. 2 $I_D - V_{GS}$

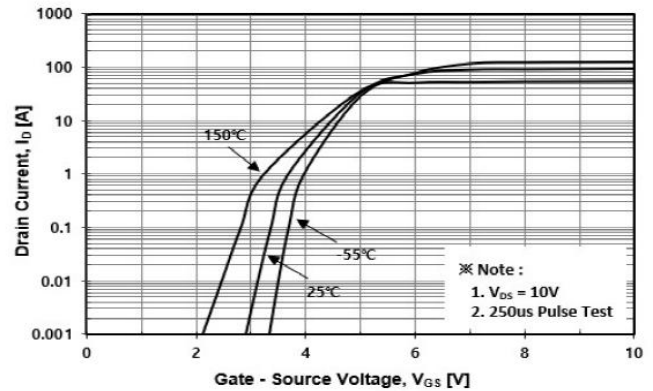


Fig. 3 $R_{DS(ON)} - I_D$

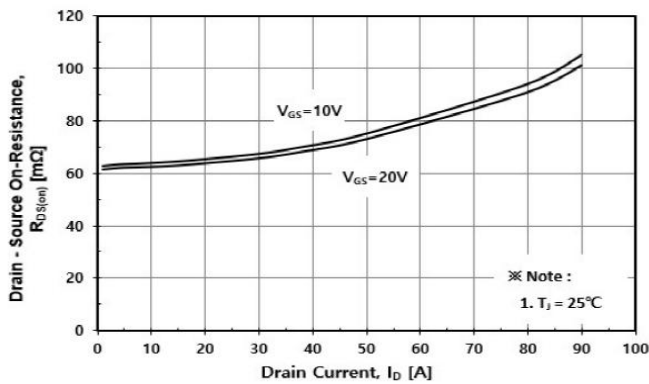


Fig. 4 $I_S - V_{SD}$

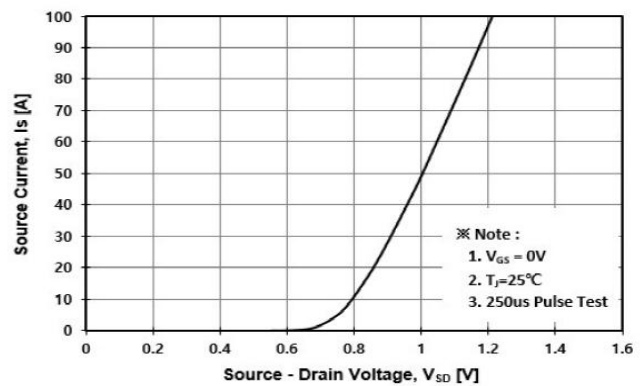


Fig. 5 Capacitance - V_{DS}

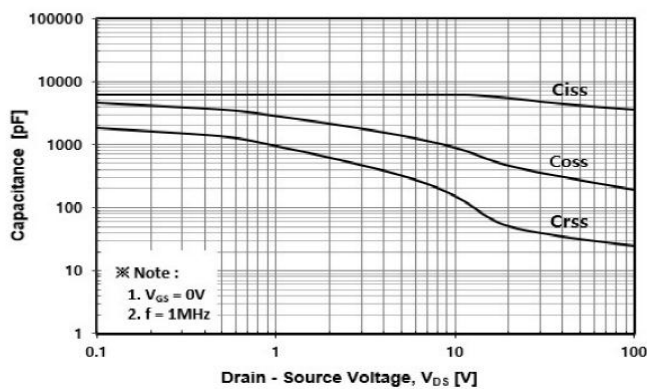
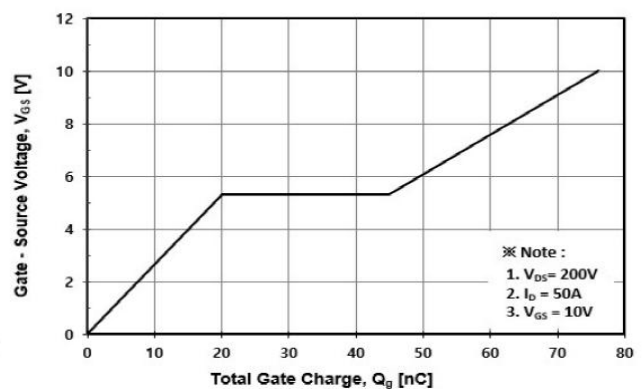


Fig. 6 $V_{GS} - Q_G$



Typical Electrical Characteristics Curves

Fig. 7 $BV_{DSS} - T_J$

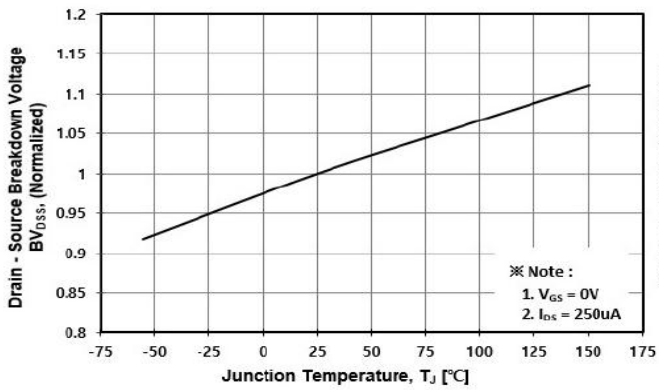


Fig. 8 $R_{DS(ON)} - T_J$

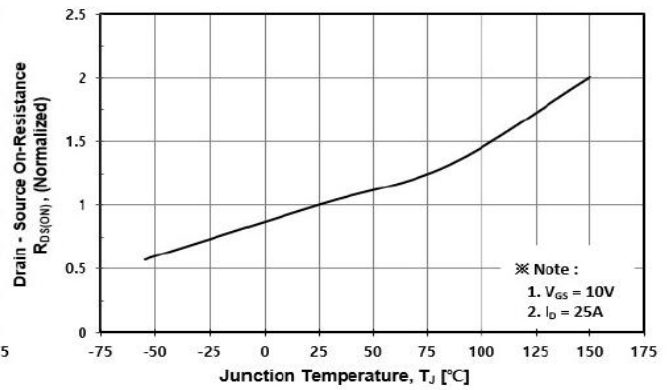


Fig. 9 $I_D - T_C$

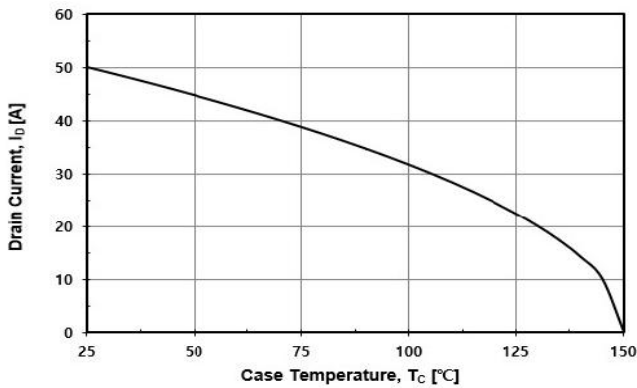


Fig. 10 Safe Operating Area

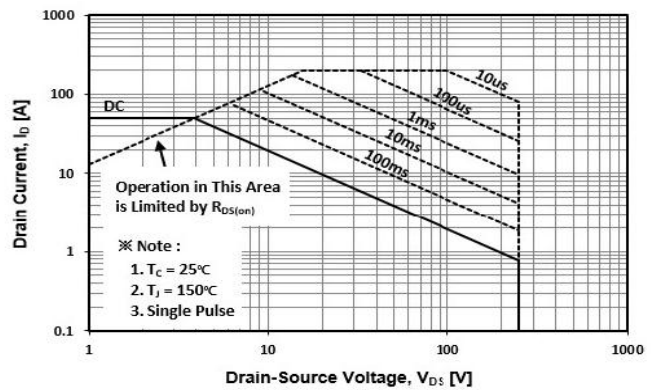


Fig. 11 Transient Thermal Impedance

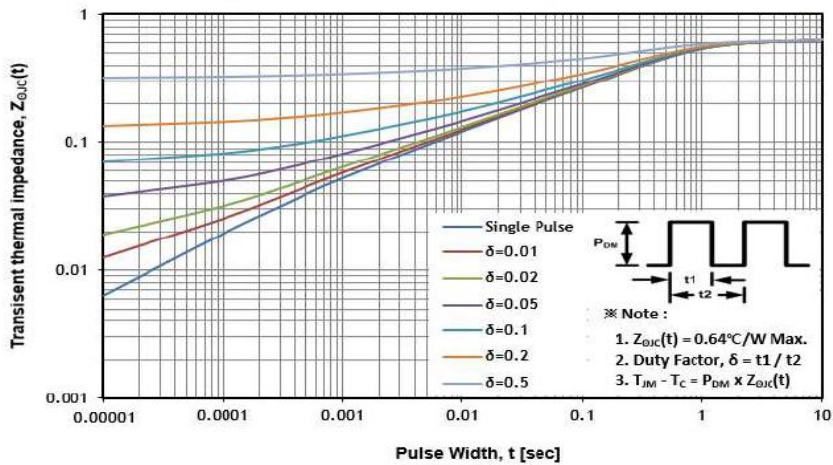


Fig. 12 Gate Charge Test Circuit & Waveform

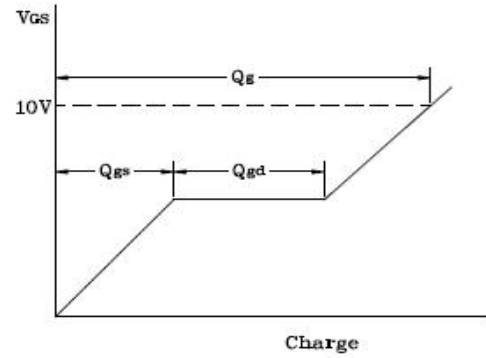
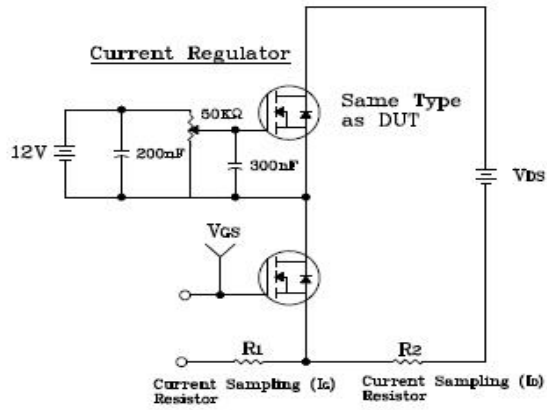


Fig. 13 Resistive Switching Test Circuit & Waveform

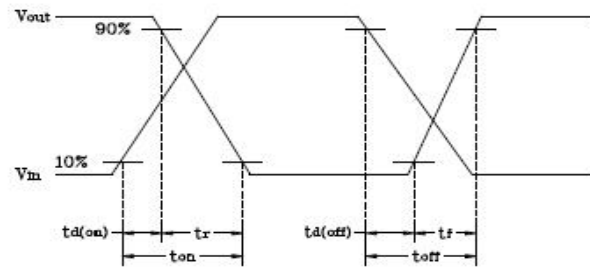
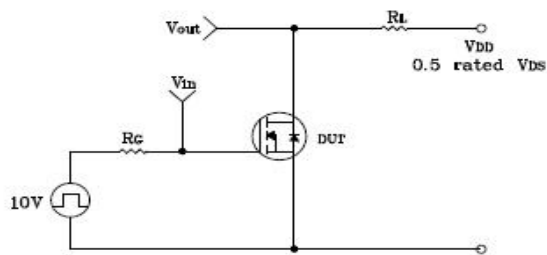


Fig. 14 E_{AS} Test Circuit & Waveform

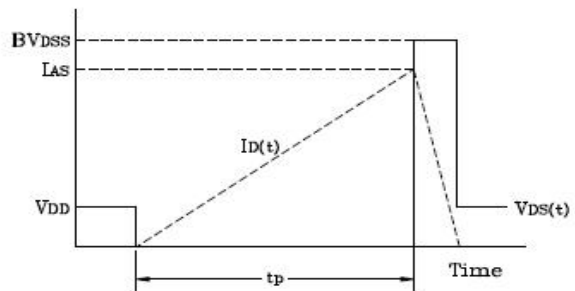
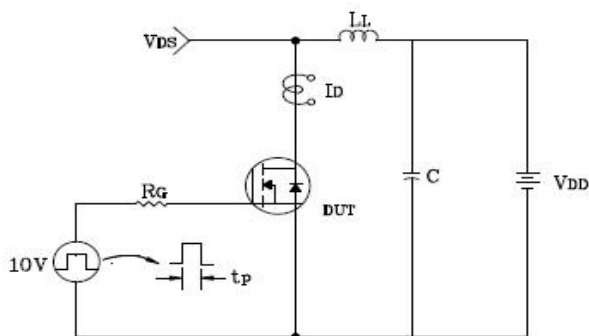


Fig. 15 Diode Reverse Recovery Time Test Circuit & Waveform

